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RECRUITMENT FOR THE POST OF JUNIOR TECHNICIAN (Electronics & Instrumentation)

SYLLABUS FOR TEST

Section 1: Networks, Signals and Systems

Network solution methods: nodal and mesh analysis; Network theorems: superposition, Thevenin and Norton's, maximum power transfer; Wye-Delta transformation; Steady state sinusoidal analysis using phasors; Time domain analysis of simple linear circuits; Solution of network equations using Laplace transform; Frequency domain analysis of RLC circuits; Linear 2-port network parameters: driving point and transfer functions; State equations for networks.

Continuous-time signals: Fourier series and Fourier transform representations, sampling theorem and applications; Discrete-time signals: discrete-time Fourier transform (DTFT), DFT, FFT, Z-transform, interpolation of discrete-time signals; LTI systems: definition and properties, causality, stability, impulse response, convolution, poles and zeros, parallel and cascade structure, frequency response, group delay, phase delay, digital filter design techniques.

Section 2: Electronic Devices

Energy bands in intrinsic and extrinsic silicon; Carrier transport: diffusion current, drift current, mobility and resistivity; Generation and recombination of carriers; Poisson and continuity equations; P-N junction, Zener diode, BJT, MOS capacitor, MOSFET, LED, photo diode and solar cell; Integrated circuit fabrication process: oxidation, diffusion, ion implantation, photolithography and twin-tub CMOS process.

Section 3: Analog Circuits

Small signal equivalent circuits of diodes, BJTs and MOSFETs; Simple diode circuits: clipping, clamping and rectifiers; Single-stage BJT and MOSFET amplifiers: biasing, bias stability, mid-frequency small signal analysis and frequency response; BJT and MOSFET amplifiers: multi-stage, differential, feedback, power and operational; Simple op-amp circuits; Active filters; Sinusoidal oscillators: criterion for oscillation, single-transistor and op-amp configurations; Function generators, wave-shaping circuits and 555 timers; Voltage reference circuits; Power supplies: ripple removal and regulation.

Section 4: Digital Circuits

Number systems; Combinatorial circuits: Boolean algebra, minimization of functions using Boolean identities and Karnaugh map, logic gates and their static CMOS implementations, arithmetic circuits, code converters, multiplexers, decoders and PLAs; Sequential circuits: latches and flip-flops, counters, shift-registers and finite state machines; Data converters: sample and hold circuits, ADCs and DACs; Semiconductor memories: ROM, SRAM, DRAM; 8-bit microprocessor (8085): architecture, programming, memory and I/O interfacing.

Section 5: Control Systems

Basic control system components; Feedback principle; Transfer function; Block diagram representation; Signal flow graph; Transient and steady-state analysis of LTI systems; Frequency response; Routh-Hurwitz and Nyquist stability criteria; Bode and root-locus plots; Lag, lead and lag-lead compensation; State variable model and solution of state

equation of LTI systems.

Section 6: Electromagnetics

Electrostatics; Maxwell's equations: differential and integral forms and their interpretation, boundary conditions, wave equation, Poynting vector; Plane waves and properties: reflection and refraction, polarization, phase and group velocity, propagation through various media, skin depth; Transmission lines: equations, characteristic impedance, impedance matching, impedance transformation, S-parameters, Smith chart; Waveguides: modes, boundary conditions, cut-off frequencies, dispersion relations; Antennas: antenna types, radiation pattern, gain and directivity, return loss, antenna arrays; Basics of radar; Light propagation in optical fibers.

Section 7: Electrical Circuits:

Voltage and current sources: independent, dependent, ideal and practical; v-i relationships of resistor, inductor, mutual inductor and capacitor; transient analysis of RLC circuits with dc excitation.

Kirchoff's laws, mesh and nodal analysis, superposition, Thevenin, Norton, maximum power transfer and reciprocity theorems.

Peak-, average- and rms values of ac quantities; apparent-, active- and reactive powers; phasor analysis, impedance and admittance; series and parallel resonance, locus diagrams, realization of basic filters with R, L and C elements.

One-port and two-port networks, driving point impedance and admittance, open-, and short circuit parameters.

Section 8: Signals and Systems

Periodic, aperiodic and impulse signals; Laplace, Fourier and z-transforms; transfer function, frequency response of first and second order linear time invariant systems, impulse response of systems; convolution, correlation. Discrete time system: impulse response, frequency response, pulse transfer function; DFT and FFT; basics of IIR and FIR filters.

Section 9: Control Systems

Feedback principles, signal flow graphs, transient response, steady-state-errors, Bode plot, phase and gain margins, Routh and Nyquist criteria, root loci, design of lead, lag and lead-lag compensators, state-space representation of systems; time-delay systems; mechanical, hydraulic and pneumatic system components, synchro pair, servo and stepper motors, servo valves; on-off, P, P-I, P-I-D, cascade, feedforward, and ratio controllers.

Section 10: Analog Electronics

Characteristics and applications of diode, Zener diode, BJT and MOSFET; small signal analysis of transistor circuits, feedback amplifiers. Characteristics of operational amplifiers; applications of opamps: difference amplifier, adder, subtractor, integrator, differentiator, instrumentation amplifier, precision rectifier, active filters and other circuits. Oscillators, signal generators, voltage controlled oscillators and phase locked loop.

Section 11: Digital Electronics

Combinational logic circuits, minimization of Boolean functions. IC families: TTL and CMOS. Arithmetic circuits, comparators, Schmitt trigger, multi-vibrators, sequential circuits, flip-

flops, shift registers, timers and counters; sample-and-hold circuit, multiplexer, analog-to-digital (successive approximation, integrating, flash and sigma-delta) and digital-to-analog converters (weighted R, R-2R ladder and current steering logic). Characteristics of ADC and DAC (resolution, quantization, significant bits, conversion/settling time); basics of number systems, 8-bit microprocessor and microcontroller: applications, memory and input-output interfacing; basics of data acquisition systems.

Section 12: Measurements

SI units, systematic and random errors in measurement, expression of uncertainty - accuracy and precision index, propagation of errors. PMMC, MI and dynamometer type instruments; dc potentiometer; bridges for measurement of R, L and C, Q-meter. Measurement of voltage, current and power in single and three phase circuits; ac and dc current probes; true rms meters, voltage and current scaling, instrument transformers, timer/counter, time, phase and frequency measurements, digital voltmeter, digital multimeter; oscilloscope, shielding and grounding.

Section 13: Sensors and Industrial Instrumentation

Resistive-, capacitive-, inductive-, piezoelectric-, Hall effect sensors and associated signal conditioning circuits; transducers for industrial instrumentation: displacement (linear and angular), velocity, acceleration, force, torque, vibration, shock, pressure (including low pressure), flow (differential pressure, variable area, electromagnetic, ultrasonic, turbine and open channel flow meters) temperature (thermocouple, bolometer, RTD (3/4 wire), thermistor, pyrometer and semiconductor); liquid level, pH, conductivity and viscosity measurement.

Section 14: Communication and Optical Instrumentation

Amplitude- and frequency modulation and demodulation; Shannon's sampling theorem, pulse code modulation; frequency and time division multiplexing, amplitude-, phase-, frequency-, pulse shift keying for digital modulation; optical sources and detectors: LED, laser, photo-diode, light dependent resistor and their characteristics; interferometer: applications in metrology; basics of fiber optic sensing.